	REVISIONS																			
LTR					[DESCR		٧		DATE (YR-MO-DA)			APPROVED							
A	Changes to paragraphs 3.1 and 3.5.1 to add "QD" requiremetoilerplate to reflect current requirementsrrp						luireme	ents. Up	odate			02-0	5-29			R. MON	NIN			
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STAN MICRO DRA	NDAR CIRC	RD CUIT G		CHE(Ra	CKED ay Mon	BY Inin				COLUMBUS, OHIO 43216 http://www.dscc.dla.mil										
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS		ЗLЕ	APPROVED BY Michael A. Frye				MICROCIRCUIT, LINEAR, HIGH SPEED DIFFERENTIAL VOLTAGE COMPARATOR, MONOLITHIC SILICON													
AND AGENCIES OF THE DEPARTMENT OF DEFENSE			E SE	DRA	WING 8	APPRC 38-06-0	OVAL D 3	ATE												
AMS	SC N/A			REVI	ISION I	LEVEL	4			SI	ZE A	CA	GE CC 67268	DE B		ţ	5962-	8767	'4	
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DSCC FORM 2233 APR 97

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



1.1 <u>Scope</u> . This drawing de accordance with MIL-PRF-385	escribes device requirements for M 35, appendix A.	IIL-STD-883 comp	bliant, non-JAN class level E	3 microcircuits in		
1.2 Part or Identifying Numb	per (PIN). The complete PIN is as	shown in the follo	wing example:			
5962-87674 Drawing number	01 C Device type Case outline	ine Lead fir	nish			
	(see 1.2.1) (see 1.2.2	2) (see 1.2	2.3)			
1.2.1 Device type(s). The c	levice type(s) identify the circuit fu	nction as follows:				
Device type	Generic number		Circuit function			
01	LM160		High-speed differential con	nparator		
1.2.2 Case outline(s). The	case outline(s) are as designated	in MIL-STD-1835	and as follows:			
Outline letter	Descriptive designator	Terminals	Package style			
C G P	GDIP1-T14 or CDIP2-T14 MACY1-X8 GDIP1-T8 or CDIP2-T8	14 8 8	14Dual-in-line8Can8Dual-in-line			
1.2.3 Lead finish. The lead	finish is as specified in MIL-PRF-	38535, appendix A	۸.			
1.3 Absolute maximum ratir	ngs.					
Supply voltage (V _{CC}) Peak output current (I _{OF} Differential input voltage Input voltage (V _{IN}) Storage temperature ra Lead temperature (Sold Junction temperature (T Power dissipation (P _D) Thermal resistance, jun Thermal resistance, jun Case C Case G Case P	b) $e (V_{ID})$ ering, 10 seconds) T_J) ction-to-case (θ_{JC}) ction-to-ambient (θ_{JA}): end conditions.	$\pm 8.0 \text{ V dc}$ 20 mA $\pm 5.0 \text{ V dc}$ $V_{CC} + \ge V_{IN} \ge V_{C}$ $-65^{\circ}\text{C to} +150^{\circ}\text{C}$ $\pm 260^{\circ}\text{C}$ $\pm 175^{\circ}\text{C}$ $550 \text{ mW} \underline{1}/$ See MIL-STD-1 76°C/W 166°C/W 125°C/W	835			
Supply voltage: V _{CC} + V _{CC} Ambient operating temp	perature range (T _A)	+4.5 V to +6.5 ^V 4.5 V to −6.5 ^V 55°C to +125°	V V °C			
1/ Must withstand the added P _D due to short circuit test; e.g., I _{OS} .						
		SIZE A		5962-87674		
DEFENSE SUPPLY COLUMBUS, C	CENTER COLUMBUS DHIO 43216-5000		REVISION LEVEL A	SHEET 2		

2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 -- Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883	-	Test Method Standard Microcircuits.
MIL-STD-1835	-	Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103	List of Standard Microcircuit Drawings.
MIL-HDBK-780 -	Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used. This drawing has been modified to allow the manufacturer to use the alternate die/fabrication requirements of paragraph A.3.2.2 of MIL-PRF-38535 or other alternative approved by the qualifying activity.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 <u>Case outline(s)</u>. The case outline(s) shall be in accordance with 1.2.2 herein.

3.2.2 <u>Terminal connections and logic diagram</u>. The terminal connections and logic diagram shall be as specified on figure 1.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-87674
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	T	ABLE I. Electrical performance	ce characteristic	<u>cs</u> .			
Test	Symbol	Conditions $-55^{\circ}C \le T_A \le +125^{\circ}C$ unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Logical "1" output voltage	V _{он}	$V_{CC} = \pm 4.5 V,$	1,2,3	01	2.4		V
		I _{OUT} = -320 μA					
Logical "0" output voltage	V _{OL}	$V_{CC} = \pm 4.5 V,$	1,2,3	01		0.4	V
		I _{OUT} = 6.4 mA					
Input bias current	I _{IB}	$V_{CC} = \pm 5 V$,	1,2,3	01		20	μA
		V _{IN} = 5 V					
Positive supply current	I _{CC} +	$V_{CC} = \pm 6.5 V$	1,2,3	01		32	mA
Negative supply current	I _{CC} -	$V_{CC} = \pm 6.5 V$	1,2,3	01		-16	mA
Short circuit current	I _{OS}	$V_{CC} = \pm 4.5 V$	1,2,3	01	-15	-52	mA
Input offset voltage	V _{IO}	V _{CC} = ±5.0 V	1,2,3	01	-5	5	mV
Input offset current	l _{io}	V _{CC} = ±5.0 V	1,2,3	01	-3	3	μA
Unbalanced input current <u>1</u> /	I _{IN1}	$V_{CC} = \pm 5 V,$ $V_{IN1} = 0 V, V_{IN2} = 5 V$	1,2,3	01		-1	mA
	I _{IN2}	$V_{CC} = \pm 5 V,$ $V_{IN1} = 5 V, V_{IN2} = 0 V$				-1	-
Supply voltage <u>1</u> /	V _{CC}		1,2,3	01	±4.5	±6.5	V
Supply breakdown voltage $\underline{1}/$	B _{VCC}		1,2,3	01	±8.0		V
Common mode input voltage range $1/$	V _{CM}	V _{CC} = ±6.5 V	1,2,3	01	±4.0		V
Differential input voltage range <u>1</u> /	V _{DIFF}		1,2,3	01	±5.0		V
Response time	t _{resp}	$V_{CC} = +5.0 \text{ V}, \ \underline{2}/ \ \underline{3}/$	9	01		25	ns
		$T_A = +25^{\circ}C \qquad \underline{4}/$				20	

<u>1</u>/ Parameter tested go-no-go only.

2/ Guaranteed parameter if not tested.

3/ Measured from the 50 percent point of a 30 mV_{P-P}, 10 MHz sinusoidal input to the 50 percent point of the output.

4/ Measured from the 50 percent point of a 2 V_{P-P}, 10 MHz sinusoidal input to the 50 percent point of the output.

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Case C







STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-87674
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Case P NC 1 8 VCC+ IN 22 7 OUT 1 6 OUT 2 IN 13 V_{CC} -4 5 GND FIGURE 1. <u>Terminal connections and logic diagram</u> – Continued. SIZE STANDARD 5962-87674 Α **MICROCIRCUIT DRAWING** DEFENSE SUPPLY CENTER COLUMBUS SHEET **REVISION LEVEL** COLUMBUS, OHIO 43216-5000 А 7

3.5 <u>Marking</u>. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein). For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.5.1 <u>Certification/compliance mark</u>. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used. For product built in accordance with A.3.2.2 of MIL-PRF-38535, or as modified in the manufacturer's QM plan, the "QD" certification mark shall be used in place of the "Q" or "QML" certification mark.

3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 <u>Notification of change</u>. Notification of change to DSCC-VA shall be required in accordance with MIL-PRF-38535, appendix A.

3.9 <u>Verification and review</u>. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, 8, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

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TABLE II.	Electrical test requirements.

MIL-STD-883 test requirements	Subgroups
	(in accordance with
	MIL-STD-883, method 5005,
	table I)
Interim electrical parameters	1
(method 5004)	
Final electrical test parameters	1*, 2, 3, 9
(method 5004)	
Group A test requirements	1, 2, 3, 9
(method 5005)	
Groups C and D end-point	1, 2, 3
electrical parameters	
(method 5005)	

* PDA applies to subgroup 1.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 <u>Packaging requirements</u>. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractorprepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 <u>Comments</u>. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0547.

6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 02-05-29

Approved sources of supply for SMD 5962-87674 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> /	number	PIN <u>2</u> /
5962-8767401CA	OC7V7	LM160
	<u>3</u> /	LM160J-14/883
5962-8767401GA	27014	LM160H/883
5962-8767401PA	OC7V7	LM160
	<u>3</u> /	LM160J/883

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- <u>2</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- $\underline{3}$ / Not available from an approved source of supply.

Vendor CAGE number	Vendor name and address
27014	National Semiconductor 2900 Semiconductor Dr PO BOX 58090 Santa Clara, CA 95052-8090
OC7V7	Qualified Parts Laboratory, Inc. 3605 Kifer Road Santa Clara, CA 95051

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.

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 SC2903VDR2G
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 NCV33202DMR2G

 M38510/13101BPA
 NTE925
 SC2904DR2G
 SC358DR2G
 LM358EDR2G
 AZV358MTR-G1
 AP4310AUMTR-AG1
 HA1630D02MMEL-E

 NJM358CG-TE2
 HA1630S01LPEL-E
 LM324AWPT
 HA1630Q06TELL-E
 E